

Notice of References Cited

Application/Control No.

10/054,131

Applicant(s)/Patent Under
Reexamination
HUSTED, STEPHEN

Examiner

Jimmy T Nguyen

Art Unit

3725

Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------------|----------------|
| | A | US-4,412,801 | 11-1983 | Pesch, Jurgen | 425/338 |
| | B | US-5,435,883 | 07-1995 | Myers, David A. | 156/583.9 |
| | C | US-3,960,069 | 06-1976 | Bowyer, Ralph Mitchell | 100/38 |
| | D | US-5,810,965 | 09-1998 | Fwu, Jason | 156/359 |
| | E | US-6,209,451 | 04-2001 | Van Haag et al. | 100/327 |
| | F | US-5,167,750 | 12-1992 | Myers, David A. | 156/583.9 |
| | G | US-4,365,547 | 12-1982 | McClure, Jr., George W. | 100/38 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| | N | JP-40-2070406 A | 03-1990 | Japan | Eguchi et al. | 425/143 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.